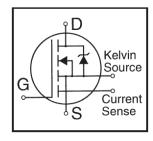
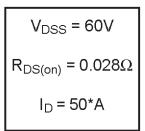
International Rectifier

IRCZ44PbF

HEXFET® Power MOSFET

- Dynamic dv/dt Rating
- Current Sense
- 175°C Operating Temperature
- Fast Switching
- Ease of Paralleling
- · Simple Drive Requirements
- Lead-Free

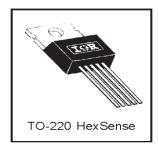




Description

Third Generation HEXFETs from International Rectifier provide the designer with the best combination of fast switching, ruggedized device, low on-resistance and cost-effectiveness.

The HEXSense device provides an accurate fraction of the drain current through the additional two leads to be used for control or protection of the device. These devices exhibit similar electrical and thermal characteristics as their IRF-series equivalent part numbers. The provision of a kelvin source connection effectively eliminates problems of common source inductance when the HEXSence is used as a fast, high-current switch in non current-sensing applications.



Absolute Maximum Ratings

	Parameter	Max.	Units	
I _D @ T _C = 25°C	50*			
I _D @ T _C = 100°C	Continuous Drain Current, V _{GS} @ 10V	37	Α	
I _{DM}	Pulsed Drain Current ①	210		
P _D @ T _C = 25°C	Power Dissipation	150	W	
	Linear Derating Factor	1.0	W/°C	
V_{GS}	Gate-to-Source Voltage	±20	V	
E AS	Single Pulse Avalanche Energy ②	30	mJ	
dv/dt	Peak Diode Recovery dv/dt ③	4.5	V/ns	
TJ	Operating Junction and	-55 to + 175		
T _{STG}	Storage Temperature Range		°C	
	Soldering Temperature, for 10 seconds	300 (1.6mm from case)		
	Mounting Torque, 6-32 or M3 screw	10 lbf•in (1.1 N•m)		

Thermal Resistance

Document Number: 91014

	Parameter	Min.	Тур.	Max.	Units
ReJC	Junction-to-Case	_	_	1.0	
R _{BCS}	Case-to-Sink, Flat, Greased Surface	_	0.50	_	°CM
Reja	Junction-to-Ambient —	_	_	62	

Electrical Characteristics @ $T_J = 25$ °C (unless otherwise specified)

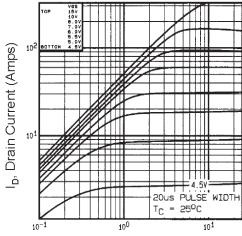
	•	•				• •
	Parameter	Min.	Тур.	Max.	Units	Conditions
V _{(BR)DSS}	Drain-to-Source Breakdown Voltage	60			V	$V_{GS} = 0V$, $I_D = 250\mu A$
ΔV _{(BR)DSS} /ΔT _J	Breakdown Voltage Temp. Coefficient		0.060		V/°C	Reference to 25°C, I _D = 1mA
R _{DS(ON)}	Static Drain-to-Source On-Resistance			0.028	Ω	V _{GS} = 10V. I _D = 31A⊕
V _{GS(th)}	Gate Threshold Voltage	2.0		4.0	V	$V_{\rm DS}$ = $V_{\rm GS}$, $I_{\rm D}$ = 250 μ A
g fs	Forward Transconductance	18			S	$V_{DS} = 25V, I_D = 31A$
	Desire to Course Looks as Course			25		$V_{DS} = 60V$. $V_{GS} = 0V$
IDSS	Drain-to-Source Leakage Current			250		V _{DS} = 48V, V _{GS} = 0V, T _J = 150°C
1	Gate-to-Source Forward Leakage			100		V _{GS} = 20V
IGSS	Gate-to-Source Reverse Leakage			-100		V _{GS} = -20V
Q _q	Total Gate Charge			95		I _D = 52A
Q _{qs}	Gate-to-Source Charge			27	пC	$V_{DS} = 48V$
Q _{gd}	Gate-to-Drain ("Miller") Charge			46		V _{GS} = 10V, See Fig. 6 and 13 ⊕
t _{d(on)}	Turn-On Delay Time		19			V _{DD} = 30V
t-	Rise Time		120			I _D = 52A
t _{d(off)}	Turn-Off Delay Time		55			$R_{\odot} = 9.1\Omega$
t:	Fall Time		86			R _D = 0.54Ω, See Fig. 10 ④
L _D	Internal Drain Inductance		4.5		nH	Between lead, 6 mm (0.25in.) from package
L _c	Internal Source Inductance		7.5			and center of die contact
Ciss	Input Capacitance		2500			$V_{GS} = 0V$
Coss	Output Capacitance		1200		pF	$V_{DS} = 25V$
Crss	Reverse Transfer Capacitance		200			f = 1.0MHz, See Fig. 5
r	Current Sensing Ratio	2460		2720		I _D = 52A. V _{GS} = 10V
Coss	Output Capacitance of Sensing Cells		9.0		pF	$V_{GS} = 0V$, $V_{DS} = 25V$. $f = 1.0MHz$

Source-Drain Ratings and Characteristics

	Parameter	Min.	Тур.	Мах.	Units	Conditions
b	Continuous Source Current			E0*		MOSFET symbol
	(Body Diode)		- -	50*		showing the
I _{SM}	Pulsed Source Current			04.0	A	integral reverse ∘↓ 📆
	(Body Diode) ①			210		p-n junction diode.
V _{SD}	Diode Forward Voltage			2.5	V	T _J = 25°C, I _S = 52A, V _{GS} = 0V ⊕
trr	Reverse Recovery Time		140	300	ns	T _{.J} = 25°C, I _F = 52A
Qr	Reverse Recovery Charge		1.2	2.8	nC	di/dt = 100A/µs ⊘
t _{on}	Forward Turn-On Time	Intr	Intrinsic turn-on time is negligible (turn-on is dominated by L _S +L _D)			

Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature. (See fig. 11)
- $\label{eq:loss} \begin{tabular}{ll} \begin$
- $\begin{tabular}{ll} \mathbb{Q} V_{DD}= 25V, starting T_J= 25°C, L= 0.013mH R_G= 25$\Omega, I_{AS}= 52A. (See Figure 12) \end{tabular}$
- 4 Pulse width $\leq 300 \mu s;$ duty cycle $\leq 2\%.$



 $V_{\rm DS}$, Drain-to-Source Voltage (Volts)

Fig. 1 Typical Output Characteristics, T_C=25°C

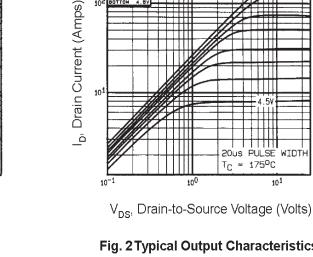
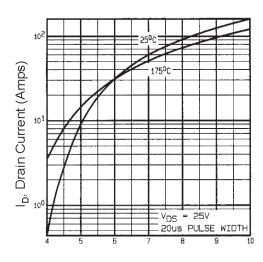
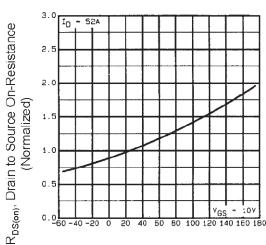


Fig. 2 Typical Output Characteristics, T_c=175°C



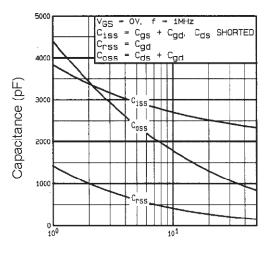
V_{DS}, Gate-to-Source Voltage (Volts)

Fig. 3 Typical Transfer Characteristics



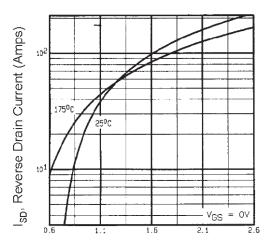
T_J, Junction Temperature (°C)

Fig. 4 Normalized On-Resistance vs. **Temperature**



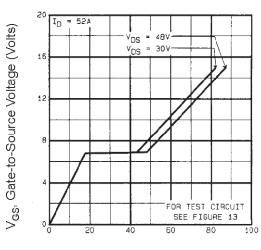
V_{DS}, Drain-to-Source Voltage (Volts)

Fig. 5 Typical Capacitance vs. Drain-to-Source Voltage



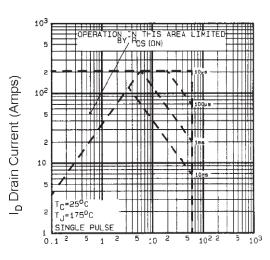
V_{SD}, Source-to-Drain Voltage (Volts)

Fig. 7 Typical Source-Drain Diode Forward Voltage



Q_G, Total Gate Charge (nC)

Fig. 6 Typical Gate Charge vs. Gate-to-Source Voltage



 V_{DS} , Drain-to-Source Voltage (Volts)

Fig. 8 Maximum Safe Operating Area

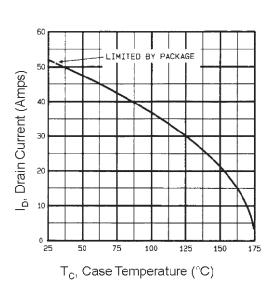


Fig. 9 Maximum Drain Current vs.

Case Temperature

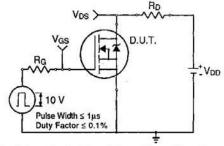


Fig 10a. Switching Time Test Circuit

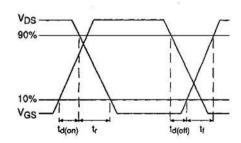
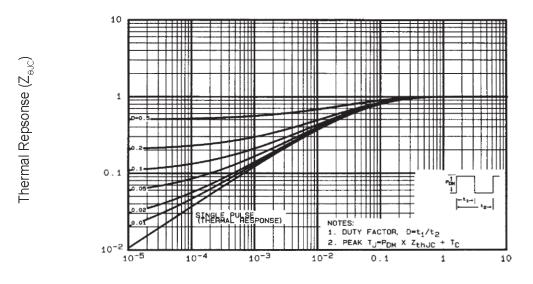


Fig 10b. Switching Time Waveforms



 $t_{\rm 1},\,{\rm Rectiangular\,\,Pulse\,\,Duration\,\,(seconds)}$ Fig. 11 Maximum Effective Transient Thermal Impedance, Junction-to-Case

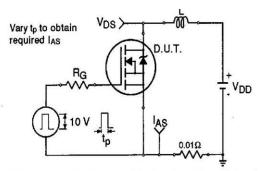


Fig 12a. Unclamped Inductive Test Circuit

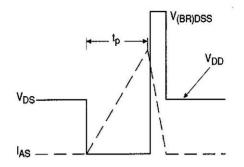


Fig 12b. Unclamped Inductive Waveforms

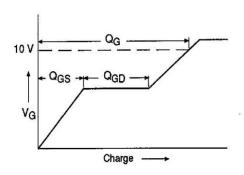


Fig 13a. Basic Gate Charge Waveform

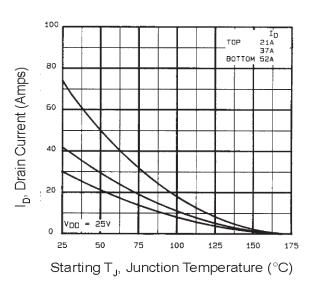


Fig. 12c Maximum Avalanche Energy vs. Drain Current

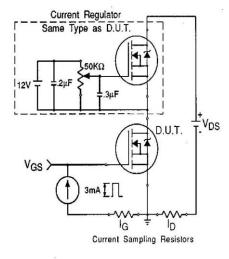


Fig 13b. Gate Charge Test Circuit

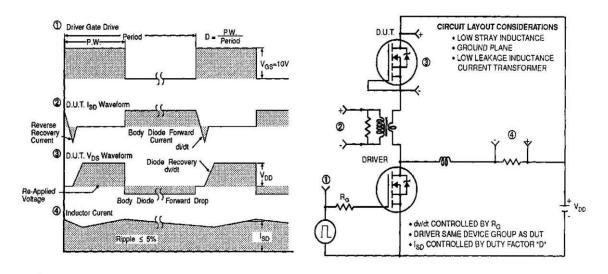


Fig 14. Peak Diode Recovery dv/dt Test Circuit

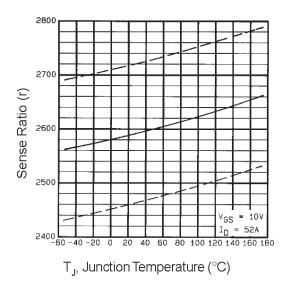


Fig. 15 Typical HEXSense Ratio vs. Junction Temperature

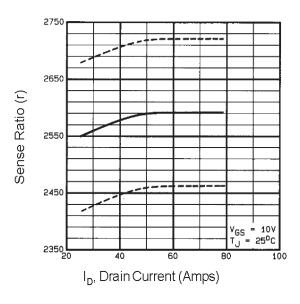
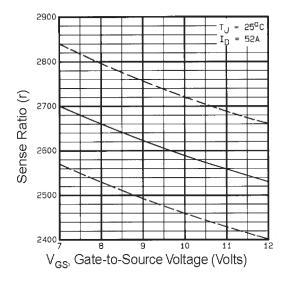


Fig. 16 Typical HEXSense Ratio vs. Drain Current

International
Rectifier



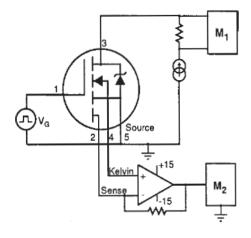


Fig. 17 Typical HEXSense Ratio vs. Gate Voltage

Fig. 18 HEXSense Ratio Test Circuit

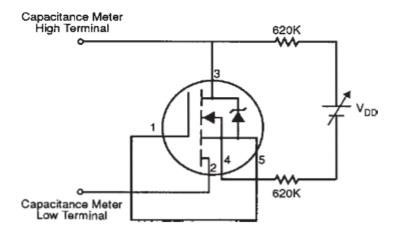
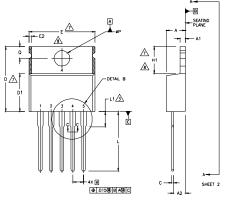
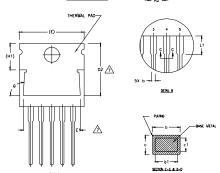


Fig. 19 HEXSense Sensing Cell Output Capacitance Test Circuit

HexsenseTO-220 5L Package Outline

(Dimensions are shown in millimeters (inches)





- DIMENSIONING AND TOLERANCING PER ASME Y14.5 M- 1994.
- DIMENSIONING AND IDLERANCING PER ASM. 114.5 M- 1994.

 DIMENSIONS ARE SHOWN IN INCHES [MILLIMETERS].

 LEAD DIMENSION AND FINISH UNCONTROLLED IN L1.

 DIMENSION D & E DO NOT INCLUDE MOLD FLASH, MOLD FLASH

 SHALL NOT EXCEED .005" (0.127) PER SIDE. THESE DIMENSIONS ARE

 MEASURED AT THE OUTERMOST EXTREMES OF THE PLASTIC BODY.
- DIMENSION b1 & c1 APPLY TO BASE METAL ONLY.

 CONTROLLING DIMENSION: INCHES.

 THERMAL PAD CONTOUR OPTIONAL WITHIN DIMENSIONS E,H1,D2 & E1
- DIMENSION E2 X H1 DEFINE A ZONE WHERE STAMPING AND SINGULATION IRREGULARITIES ARE ALLOWED.

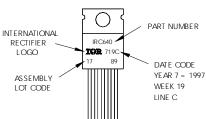
	DIMENSIONS					
SYMBOL	MILLIM	ETERS	INCHES		1	
	MIN.	MAX.	MIN.	MAX.	NOTES	
Α	3,56	4,82	,140	.190		
A1	0.51	1.40	.020	.055		
A2	2.04	2.92	.080	.115		
b	0.64	0.88	.025	.035		
b1	0.64	0.84	.025	.033	5	
С	0.36	0.61	.014	.024		
c1	0.36	0.56	.014	.022	5	
D	14,22	16,51	,560	.650	4	
D1	8.38	9.02	.330	.355		
D2	12.19	12,88	.480	.507	7	
E	9,66	10,66	.380	.420	4,7	
E1	8.38	8.89	.330	.350	7	
e	1,70	BSC	.067	BSC		
H1	5.85	6.55	.230	.270	7,8	
L	13.47	14.09	.530	.555		
L1	-	6.35	-	.250	3	
øΡ	3.54	4.08	.139	.161		
Q	2.54	3.42	.100	.135		
ø	90'-93'		90*			

Hexsense TO-220 5L Part Marking Information

EXAMPLE: THIS IS AN IRC640 WITH ASSEMBLY LOT CODE 1789 ASSEMBLED ON WW 19, 1997 IN THE ASSEMBLY LINE "C"

Document Number: 91014

Note: "P" in assembly line position indicates "Lead-Free



Data and specifications subject to change without notice.

International IOR Rectifier

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TAC Fax: (310) 252-7903 02/05

www.vishay.com



Vishay

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